



ON Semiconductor®

ISL9V3040D3S / ISL9V3040S3S / ISL9V3040P3 / ISL9V3040S3

EcoSPARK® 300mJ, 400V, N-Channel Ignition IGBT

General Description

The ISL9V3040D3S, ISL9V3040S3S, ISL9V3040P3, and ISL9V3040S3 are the next generation ignition IGBTs that offer outstanding SCIS capability in the space saving D-Pak (TO-252), as well as the industry standard D²-Pak (TO-263), and TO-262 and TO-220 plastic packages. This device is intended for use in automotive ignition circuits, specifically as a coil driver. Internal diodes provide voltage clamping without the need for external components.

EcoSPARK® devices can be custom made to specific clamp voltages. Contact your nearest On Semiconductor sales office for more information.

Formerly Developmental Type 49362

Applications

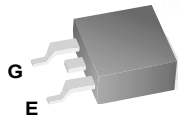
- Automotive Ignition Coil Driver Circuits
- Coil- On Plug Applications

Features

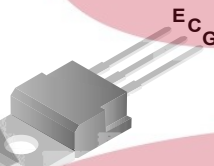
- Space saving D-Pak package availability
- SCIS Energy = 300mJ at T_J = 25°C
- Logic Level Gate Drive

Package

JEDEC TO-263AB
D²-Pak



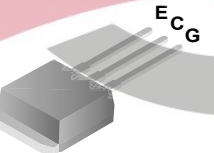
JEDEC TO-220AB



JEDEC TO-252AA
D-Pak

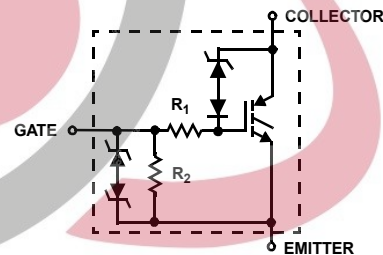


JEDEC TO-262AA



COLLECTOR
(FLANGE)

Symbol



Device Maximum Ratings

T_A = 25°C unless otherwise noted

| Symbol | Parameter | Rating | Units |
|----------------------|---|------------|-------|
| BV _{CER} | Collector to Emitter Breakdown Voltage (I _C = 1 mA) | 430 | V |
| BV _{ECS} | Emitter to Collector Voltage - Reverse Battery Condition (I _C = 10 mA) | 24 | V |
| E _{SCIS25} | At Starting T _J = 25°C, I _{SCIS} = 14.2A, L = 3.0 mHy | 300 | mJ |
| E _{SCIS150} | At Starting T _J = 150°C, I _{SCIS} = 10.6A, L = 3.0 mHy | 170 | mJ |
| I _{C25} | Collector Current Continuous, At T _C = 25°C, See Fig 9 | 21 | A |
| I _{C110} | Collector Current Continuous, At T _C = 110°C, See Fig 9 | 17 | A |
| V _{GEM} | Gate to Emitter Voltage Continuous | ±10 | V |
| P _D | Power Dissipation Total T _C = 25°C | 150 | W |
| | Power Dissipation Derating T _C > 25°C | 1.0 | W/°C |
| T _J | Operating Junction Temperature Range | -40 to 175 | °C |
| T _{STG} | Storage Junction Temperature Range | -40 to 175 | °C |
| T _L | Max Lead Temp for Soldering (Leads at 1.6mm from Case for 10s) | 300 | °C |
| T _{pkg} | Max Lead Temp for Soldering (Package Body for 10s) | 260 | °C |
| ESD | Electrostatic Discharge Voltage at 100pF, 1500Ω | 4 | kV |

Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|---------------|----------|-----------|------------|----------|
| V3040D | ISL9V3040D3ST | TO-252AA | 330mm | 16mm | 2500 |
| V3040S | ISL9V3040S3ST | TO-263AB | 330mm | 24mm | 800 |
| V3040P | ISL9V3040P3 | TO-220AB | Tube | N/A | 50 |
| V3040S | ISL9V3040S3 | TO-262AA | Tube | N/A | 50 |
| V3040D | ISL9V3040D3S | TO-252AA | Tube | N/A | 75 |
| V3040S | ISL9V3040S3S | TO-263AB | Tube | N/A | 50 |

Electrical Characteristics $T_A = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|--------|-----------|-----------------|-----|-----|-----|-------|
|--------|-----------|-----------------|-----|-----|-----|-------|

Off State Characteristics

| | | | | | | | |
|------------|--|--|---|----------|-----|----------|---------------------|
| BV_{CER} | Collector to Emitter Breakdown Voltage | $I_C = 2\text{mA}$, $V_{GE} = 0$, $R_G = 1\text{K}\Omega$, See Fig. 15 $T_J = -40$ to 150°C | 370 | 400 | 430 | V | |
| BV_{CES} | Collector to Emitter Breakdown Voltage | $I_C = 10\text{mA}$, $V_{GE} = 0$, $R_G = 0$, See Fig. 15 $T_J = -40$ to 150°C | 390 | 420 | 450 | V | |
| BV_{ECS} | Emitter to Collector Breakdown Voltage | $I_C = -75\text{mA}$, $V_{GE} = 0\text{V}$, $T_C = 25^\circ\text{C}$ | 30 | - | - | V | |
| BV_{GES} | Gate to Emitter Breakdown Voltage | $I_{GES} = \pm 2\text{mA}$ | ± 12 | ± 14 | - | V | |
| I_{CER} | Collector to Emitter Leakage Current | $V_{CER} = 250\text{V}$, $R_G = 1\text{K}\Omega$, See Fig. 11 | $T_C = 25^\circ\text{C}$ $T_C = 150^\circ\text{C}$ | - | - | 25 1 | μA mA |
| I_{ECS} | Emitter to Collector Leakage Current | $V_{EC} = 24\text{V}$, See Fig. 11 | $T_C = 25^\circ\text{C}$ $T_C = 150^\circ\text{C}$ | - | - | 1 40 | mA mA |
| R_1 | Series Gate Resistance | | - | 70 | - | Ω | |
| R_2 | Gate to Emitter Resistance | | 10K | - | 26K | Ω | |

On State Characteristics

| | | | | | | | |
|---------------|---|--|---|---|------|------|---|
| $V_{CE(SAT)}$ | Collector to Emitter Saturation Voltage | $I_C = 6\text{A}$, $V_{GE} = 4\text{V}$ | $T_C = 25^\circ\text{C}$, See Fig. 3 | - | 1.25 | 1.60 | V |
| $V_{CE(SAT)}$ | Collector to Emitter Saturation Voltage | $I_C = 10\text{A}$, $V_{GE} = 4.5\text{V}$ | $T_C = 150^\circ\text{C}$, See Fig. 4 | - | 1.58 | 1.80 | V |
| $V_{CE(SAT)}$ | Collector to Emitter Saturation Voltage | $I_C = 15\text{A}$, $V_{GE} = 4.5\text{V}$ | $T_C = 150^\circ\text{C}$ | - | 1.90 | 2.20 | V |

Dynamic Characteristics

| | | | | | | | |
|--------------|-----------------------------------|--|---|-------------|---|------------|--------|
| $Q_{G(ON)}$ | Gate Charge | $I_C = 10\text{A}$, $V_{CE} = 12\text{V}$, $V_{GE} = 5\text{V}$, See Fig. 14 | - | 17 | - | nC | |
| $V_{GE(TH)}$ | Gate to Emitter Threshold Voltage | $I_C = 1.0\text{mA}$, $V_{CE} = V_{GE}$, See Fig. 10 | $T_C = 25^\circ\text{C}$ $T_C = 150^\circ\text{C}$ | 1.3 0.75 | - | 2.2 1.8 | V V |
| V_{GEP} | Gate to Emitter Plateau Voltage | $I_C = 10\text{A}$, $V_{CE} = 12\text{V}$ | - | 3.0 | - | V | |

Switching Characteristics

| | | | | | | |
|---------------|---------------------------------------|--|---|-----|-----|---------------|
| $t_{d(ON)R}$ | Current Turn-On Delay Time-Resistive | $V_{CE} = 14\text{V}$, $R_L = 1\Omega$ | - | 0.7 | 4 | μs |
| t_{rR} | Current Rise Time-Resistive | $V_{GE} = 5\text{V}$, $R_G = 1\text{K}\Omega$ $T_J = 25^\circ\text{C}$, See Fig. 12 | - | 2.1 | 7 | μs |
| $t_{d(OFF)L}$ | Current Turn-Off Delay Time-Inductive | $V_{CE} = 300\text{V}$, $L = 500\mu\text{H}$, | - | 4.8 | 15 | μs |
| t_{fL} | Current Fall Time-Inductive | $V_{GE} = 5\text{V}$, $R_G = 1\text{K}\Omega$ $T_J = 25^\circ\text{C}$, See Fig. 12 | - | 2.8 | 15 | μs |
| SCIS | Self Clamped Inductive Switching | $T_J = 25^\circ\text{C}$, $L = 3.0\text{mH}$, $R_G = 1\text{K}\Omega$, $V_{GE} = 5\text{V}$, See Fig. 1 & 2 | - | - | 300 | mJ |

Thermal Characteristics

| | | | | | | |
|-----------------|----------------------------------|--------------|---|---|-----|--------------------|
| $R_{\theta JC}$ | Thermal Resistance Junction-Case | All packages | - | - | 1.0 | $^\circ\text{C/W}$ |
|-----------------|----------------------------------|--------------|---|---|-----|--------------------|

Typical Performance Curves

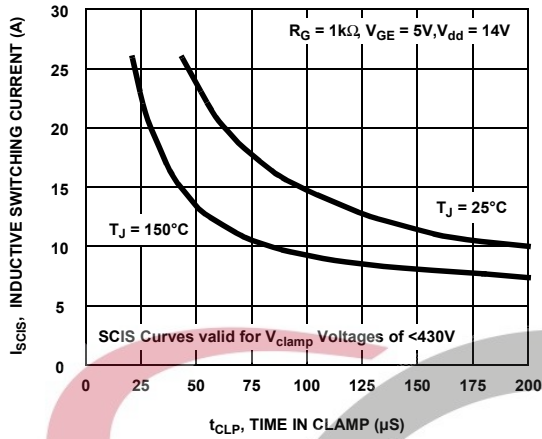


Figure 1. Self Clamped Inductive Switching Current vs Time in Clamp

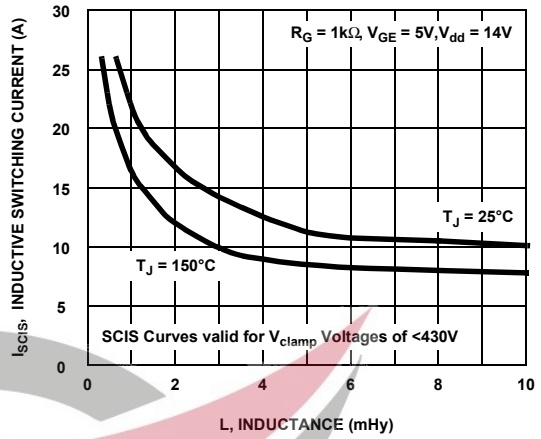


Figure 2. Self Clamped Inductive Switching Current vs Inductance

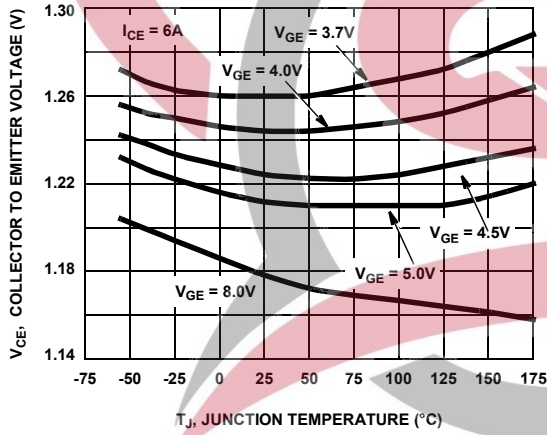


Figure 3. Collector to Emitter On-State Voltage vs Junction Temperature

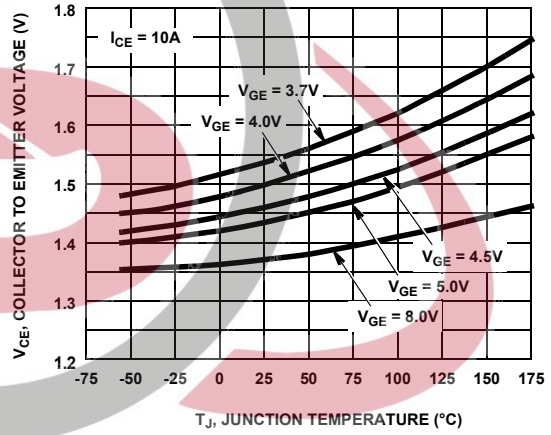


Figure 4. Collector to Emitter On-State Voltage vs Junction Temperature

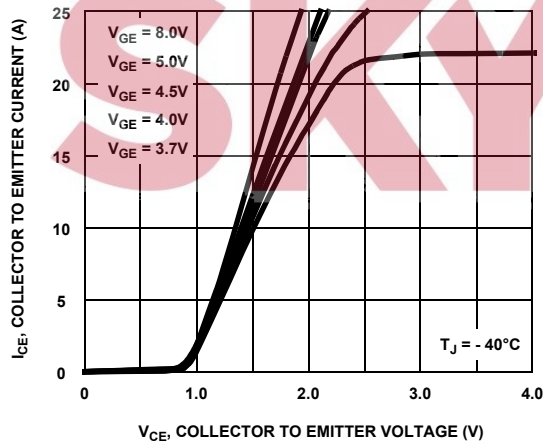


Figure 5. Collector to Emitter On-State Voltage vs Collector Current

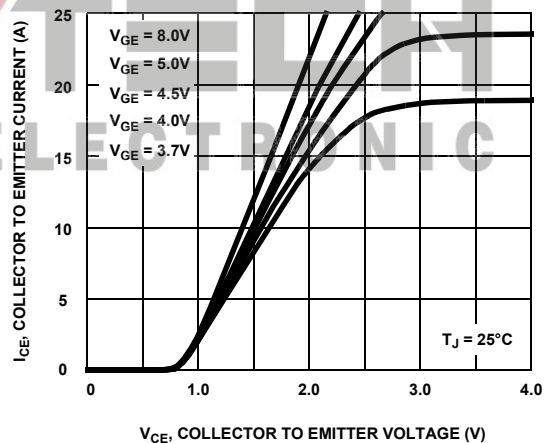


Figure 6. Collector to Emitter On-State Voltage vs Collector Current

Typical Performance Curves (Continued)

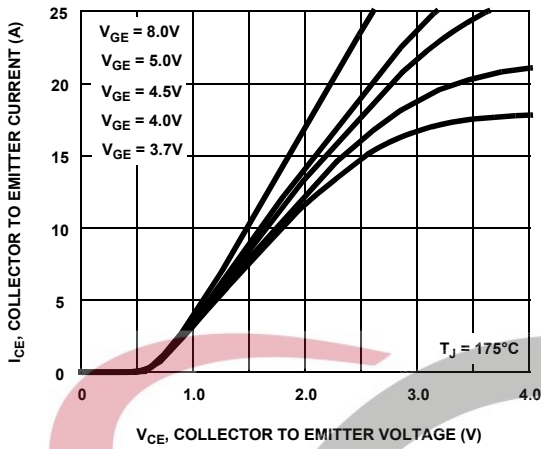


Figure 7. Collector to Emitter On-State Voltage vs Collector Current

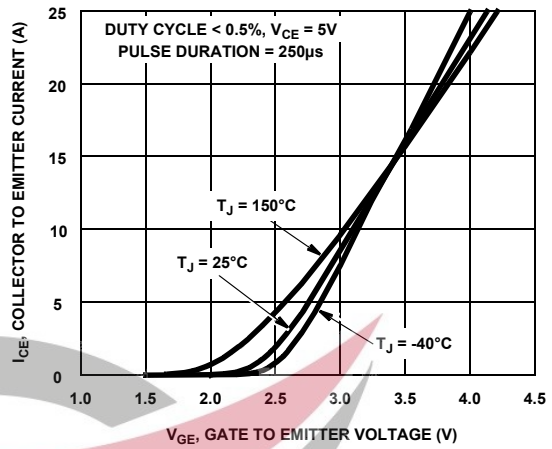


Figure 8. Transfer Characteristics

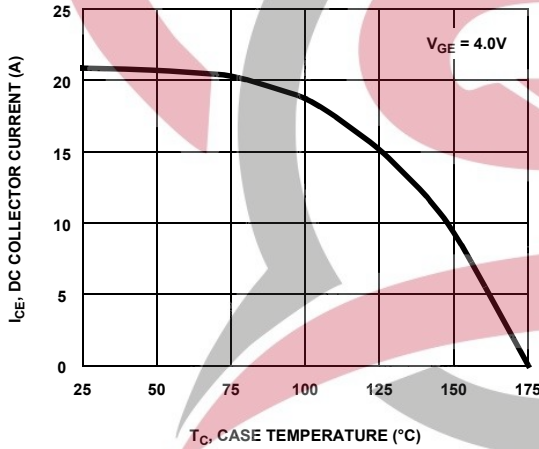


Figure 9. DC Collector Current vs Case Temperature

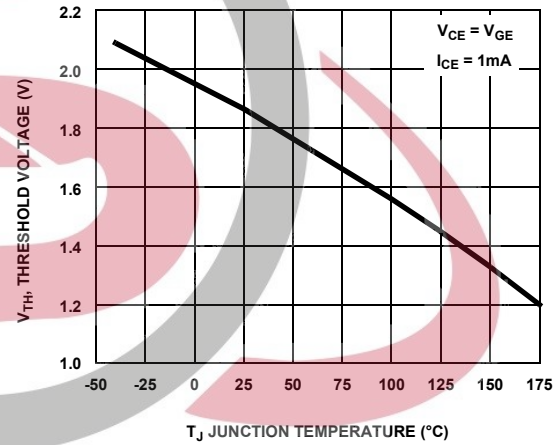


Figure 10. Threshold Voltage vs Junction Temperature

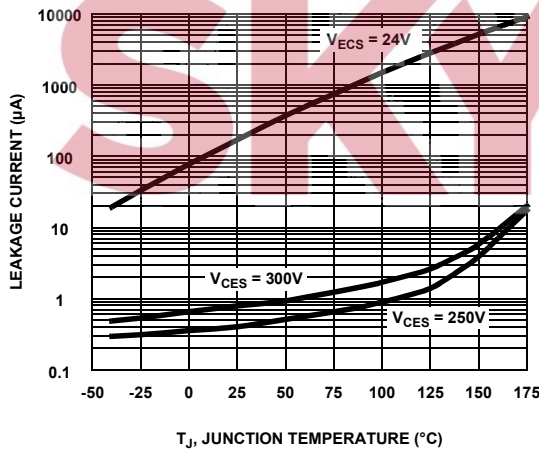


Figure 11. Leakage Current vs Junction Temperature

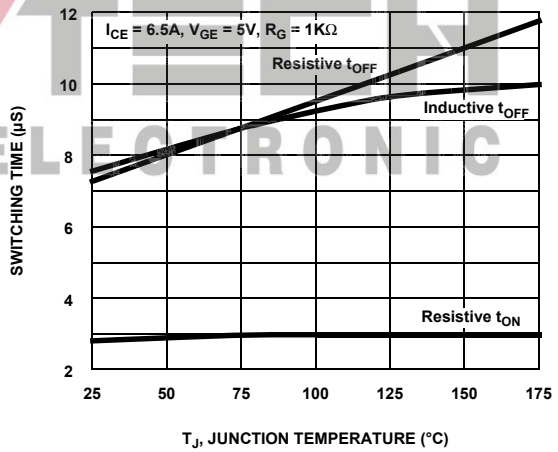


Figure 12. Switching Time vs Junction Temperature

Typical Performance Curves (Continued)

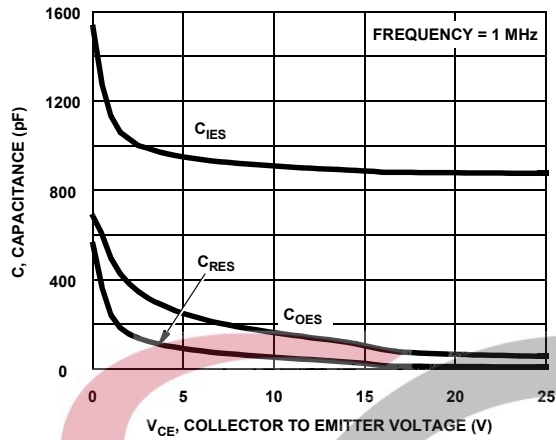


Figure 13. Capacitance vs Collector to Emitter Voltage

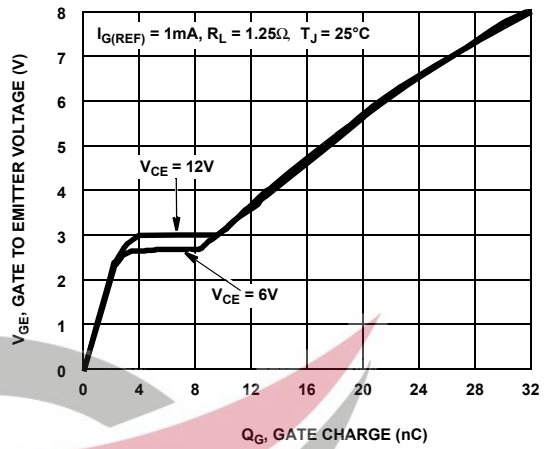


Figure 14. Gate Charge

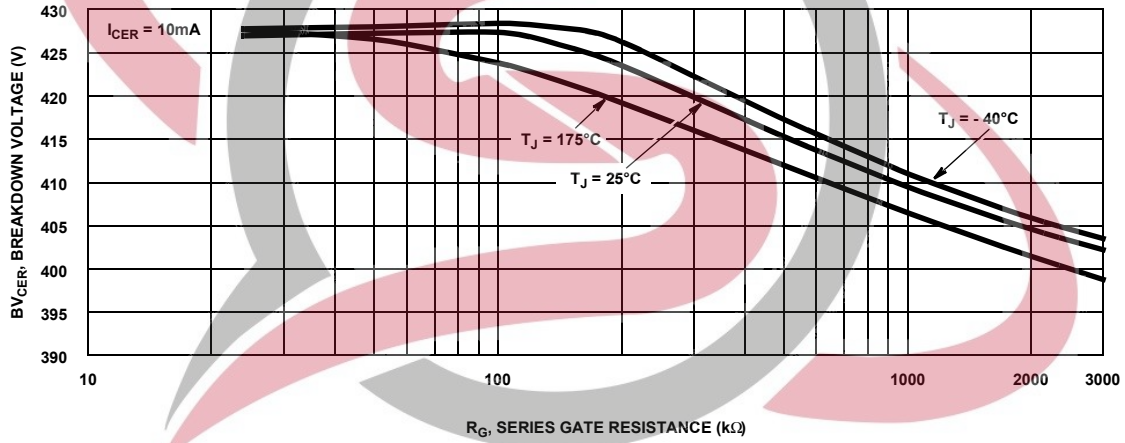


Figure 15. Breakdown Voltage vs Series Gate Resistance

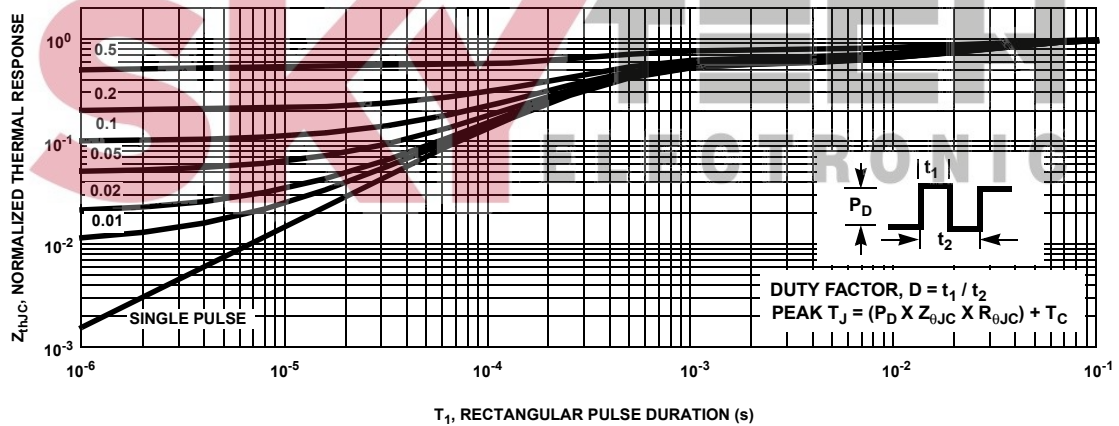


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

Test Circuit and Waveforms

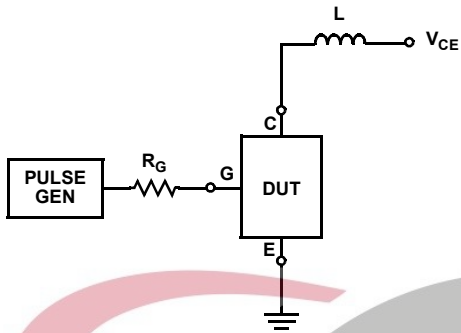


Figure 17. Inductive Switching Test Circuit

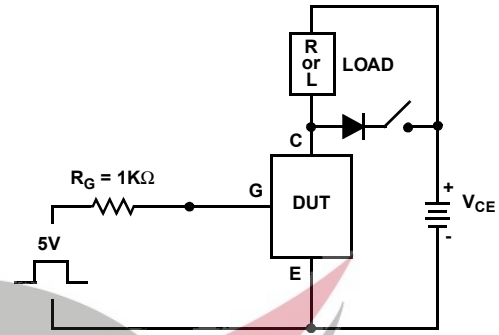


Figure 18. t_{ON} and t_{OFF} Switching Test Circuit

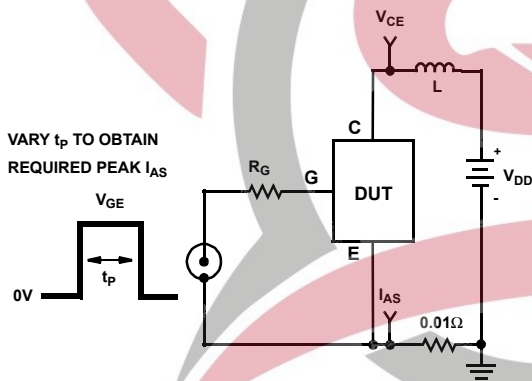


Figure 19. Energy Test Circuit

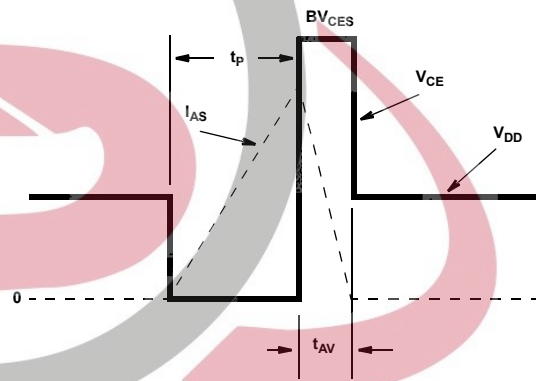


Figure 20. Energy Waveforms

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SPICE Thermal Model

REV 7 March 2002

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ISL9V3040S3

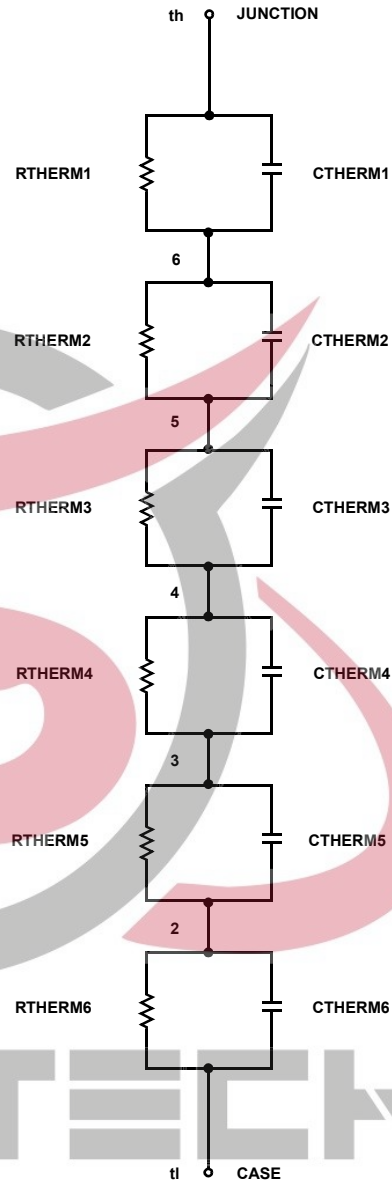
```
CTHERM1 th 6 2.1e -3  
CTHERM2 6 5 1.4e -1  
CTHERM3 5 4 7.3e -3  
CTHERM4 4 3 2.1e -1  
CTHERM5 3 2 1.1e -1  
CTHERM6 2 tl 6.2e +6
```

```
RTHERM1 th 6 1.2e -1  
RTHERM2 6 5 1.9e -1  
RTHERM3 5 4 2.2e -1  
RTHERM4 4 3 6.0e -2  
RTHERM5 3 2 5.8e -2  
RTHERM6 2 tl 1.6e -3
```

SABER Thermal Model

SABER thermal model
ISL9V3040D3S / ISL9V3040S3S / ISL9V3040P3 /
ISL9V3040S3

```
template thermal_model th tl  
thermal_c th, tl  
{  
  ctherm.ctherm1 th 6 = 2.1e -3  
  ctherm.ctherm2 6 5 = 1.4e -1  
  ctherm.ctherm3 5 4 = 7.3e -3  
  ctherm.ctherm4 4 3 = 2.2e -1  
  ctherm.ctherm5 3 2 = 1.1e -1  
  ctherm.ctherm6 2 tl = 6.2e +6  
  
  rtherm.rtherm1 th 6 = 1.2e -1  
  rtherm.rtherm2 6 5 = 1.9e -1  
  rtherm.rtherm3 5 4 = 2.2e -1  
  rtherm.rtherm4 4 3 = 6.0e -2  
  rtherm.rtherm5 3 2 = 5.8e -2  
  rtherm.rtherm6 2 tl = 1.6e -3  
}
```




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